Am8127

AmZ8000 Clock Generator

DISTINCTIVE CHARACTERISTICS

- **High-drive high-level clock output**
  Special output provides clock signal matched to requirements of AmZ8000* CPU (4MHz and some 6MHz applications), MMU and DMA devices.
- **Synchronized WAIT state and time-out controls**
  On-chip logic generates WAIT signal under control of Halt, Single-step, Status and Ready signals. Automatic time-out of peripheral wait requests.
- **Four TTL-level clocks**
  Generates synchronized TTL compatible clocks at 16MHz, 2MHz and 1MHz to drive memory circuits and LSI peripheral devices. An additional TTL clock is synchronized with the CPU high-level clock for registers, latches and other peripherals.

GENERAL DESCRIPTION

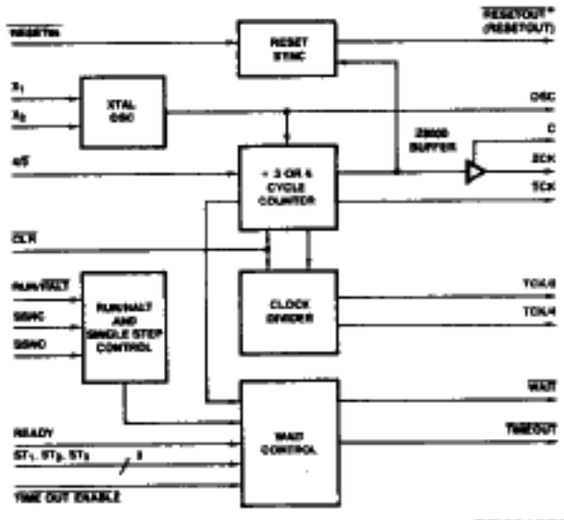
The Am8127 Clock Generator and Controller provides the clock oscillator, frequency dividers and clock drivers for the complete array of AmZ8000 CPUs, peripherals and memory system configurations. In addition to the special 4MHz output driver for the AmZ8001* and AmZ8002* CPUs, a standard buffered TTL 16MHz oscillator output is provided for a dynamic memory timing and control. In addition to 4MHz applications, the Am8127 will also function in some 6MHz Z8000 applications. The Am8127 forms an integral part of the dynamic memory support chip set including the Am8163 EDC and Refresh Controller, Am2964 Dynamic Memory Controller, Am2960 Error Detection and Correction Unit and Am2961/Am2962 EDC Bus Buffers. The oscillator is designed to operate with a 16MHz crystal or with external 16MHz drive. The Am8127 uses an internal divide-by-4 to provide 4MHz clock drive to the AmZ8001/AmZ8002 CPU. Additional dividers generate synchronous buffered 4, 2 and 1MHz clock outputs for use by peripheral devices. The clock divider counters are clearable to allow synchronization of the multiple clock outputs.

The controller functions include $\overline{\text{RESET}}$, RUN/$\overline{\text{HALT}}$, SINGLE-STEP, READY and a READY TIMEOUT counter which limits a peripheral's wait request to 16 clock cycles. The CPU's $\overline{\text{WAIT}}$ input is controlled by RUN/$\overline{\text{HALT}}$, Single-Step, Status and READY. When RUN/$\overline{\text{HALT}}$ is LOW the Am8127 drives the $\overline{\text{WAIT}}$ output LOW causing the CPU to add wait states (TW). The READY input is used by peripherals to request wait states. The active LOW input timeout enable, $\overline{\text{TOEN}}$, is used to force $\overline{\text{TIME-OUT}}$ LOW and WAIT HIGH 16 clock cycles after a peripheral has requested a wait but fails to release the request. The CPU status lines ST_1, ST_2 and ST_3 are decoded in the Am8127 to disable the $\overline{\text{TIMEOUT}}$ counter during CPU "Internal Operations" and during refresh.

The 4/3 input controls the clock duty cycle. An internal pull-up resistor pulls this input high for AmZ8000 CPUs. A LOW input causes the cycle counter to output a 33% duty cycle.

BLOCK DIAGRAM

CLOCK GENERATOR



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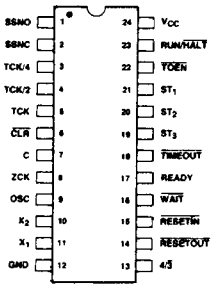
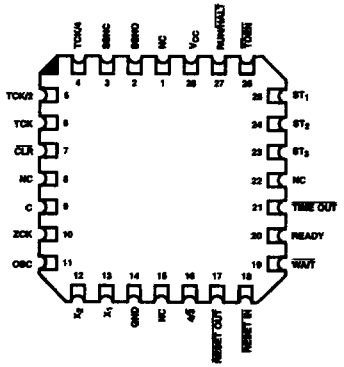
*$\overline{\text{RESETOUT}}$ is active LOW when 4/$\overline{3}$ = HIGH

CONNECTION DIAGRAM
Top View



CD001850

Leadless Chip Carrier



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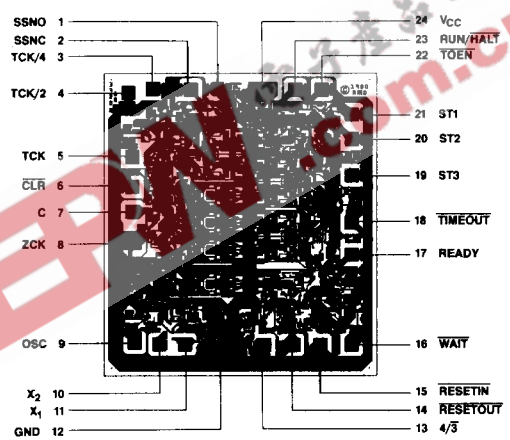
24 Pin 0.3″ wide
Pin 1 is marked for orientation

METALLIZATION AND PAD LAYOUT



DIE SIZE 0.098″ x 0.088″

ORDERING INFORMATION

AMD products are available in several packages and operating ranges. The order number is formed by a combination of the following: Device number, speed option (if applicable), package type, operating range and screening option (if desired).

Am8127 **D** **C** **B**

- **B** — Screening Option
  - Blank – Standard processing
  - B – Burn-in
- **C** — Temperature (See Operating Range)
  - C – Commercial (0°C to +70°C)
  - M – Military (–55°C to +125°C)
- **D** — Package
  - D – 24-pin Ceramic SLIMDIP (D-24-SLIM)
  - L – 28-pin Leadless Chip Carrier (L-28-1)
  - X – Dice
- **Am8127** — Device type
  - AmZ8000 Clock Generator

Valid Combinations	
Am8127	DC, DCB, DM, DMB LC, LCB, LM, LMB XC, XM

Valid Combinations

Consult the AMD sales office in your area to determine if a device is currently available in the combination you wish.

PIN DESCRIPTION

Pin No.	Name	I/O	Description
8	ZCK	O	Buffered clock output for CPU and peripherals. This output has under/overshoot control and provides the high level output voltage required (V_{CC} – 0.4V). This output is capable of driving multiple CPU clock inputs (or DMA, MMU, etc).
7	C	I	Bootstrap input. The capacitor C_B is connected from the ZCK clock output to C to provide faster ZCK risetime.
5	TCK	O	TTL level buffered clock output. TCK is the same frequency as ZCK and is synchronized with ZCK. TCK is in phase with ZCK when the 4/$\overline{3}$ duty cycle control input is HIGH (50% duty cycle) and out of phase with ZCK when 4/$\overline{3}$ is LOW (33% ZCK duty cycle).
3, 4	TCK/2, TCK/4	O	TTL buffered clocks for peripherals. TCK/2 and TCK/4 are 1/2 and 1/4 the TCK frequency and are synchronized with the rising edge of TCK.
9	OSC	O	The clock oscillator TTL buffered output. This output provides a high speed clock for dynamic memory timing (e.g. AmZ8000 uses this output to generate $\overline{RAS}$/MUX-Select/$\overline{CAS}$ timing for dynamic RAMs) or other system application. The ZCK and TCK outputs are synchronized to the OSC rising edge.
13	4/$\overline{3}$	I	Clock duty cycle control for ZCK and TCK. A HIGH input (no connection – input has internal pull-up) will result in a 50% duty cycle for AmZ8000 application. A LOW input will cause a 33% duty cycle ZCK output.
6	$\overline{CLR}$	I	The clear active LOW input for internal counters. A LOW input meeting set-up and hold time requirements will clear the internal clock counters on the rising edge of OSC.
16	$\overline{WAIT}$	O	The $\overline{WAIT}$ output for connection to the CPU $\overline{WAIT}$ input. This latched output controls when the CPU enters wait states in response to the READY, ST_1, ST_2, ST_3, RUN/$\overline{HALT}$ and Single Step inputs.
17	READY	I	The active HIGH READY input is used by peripherals to request wait states. Ready inputs must meet the wait latch set-up and hold time requirements.
18	$\overline{TIMEOUT}$	O	The Timeout Counter active LOW output. The Timeout Counter counts ZCK/TCK clock cycles and is used to force $\overline{WAIT}$ HIGH 15 clock cycles after a peripheral has requested a wait but has failed to release the request. This output is normally used to interrupt the CPU.
22	$\overline{TOEN}$	I	The Timeout Enable active LOW input. A LOW input allows the Timeout Counter to count, causes the $\overline{TIMEOUT}$ output to go LOW for one ZCK/TCK clock period after 15 cycles and forces $\overline{WAIT}$ HIGH at the rising edge of the 16th cycle. A HIGH input disables the counter and allows $\overline{WAIT}$ to be controlled by the READY, RUN/$\overline{HALT}$ and Single Step inputs.
14	$\overline{RESET\text{-}OUT}$ (RESET-OUT)	O	The Reset Output to the CPU. It is active LOW when the 4/$\overline{3}$ input is HIGH and active HIGH when the 4/$\overline{3}$ input is LOW.
15	$\overline{RESETIN}$	I	The active LOW Reset Input. A LOW input will cause $\overline{RESETOUT}$ to go LOW synchronous with ZCK ↓. Pushbutton reset is implemented by momentarily grounding $\overline{RESETIN}$. Power-up reset is implemented by connecting a capacitor from $\overline{RESETIN}$ to ground. Capacitor values from 10μF to 22μF will provide a power-up of less than one second.
23	RUN/$\overline{HALT}$	I	A debounced input to allow halt and Single Step control modes. A HIGH input allows the CPU to run. A LOW input forces the $\overline{WAIT}$ output LOW causing the CPU to enter continuous wait states until the ZCK period after RUN/$\overline{HALT}$ is returned to HIGH.
1	SSNO, SSNC	I	Single Step control inputs. These debounced input allow the CPU to Single Step from one wait state to the next by momentarily disconnecting SSNC from ground and grounding SSNO. RUN/$\overline{HALT}$ must be LOW for Single Step operation.
19, 20, 21	ST_1, ST_2, ST_3	I	Status inputs from AmZ8000 CPU's and peripherals. Continuous LOW inputs indicate that the CPU is executing "internal operation" or "refresh." During this time the time out is disabled to avoid signaling an inappropriate interrupt. The status inputs are subject to the set-up and hold time requirements of the $\overline{WAIT}$ latch.
10, 11	X_1, X_2	I	External crystal connections (see application section). X_1 may be driven directly by a TTL input.

*$\overline{RESETOUT}$ is active LOW when 4/$\overline{3}$ = HIGH.

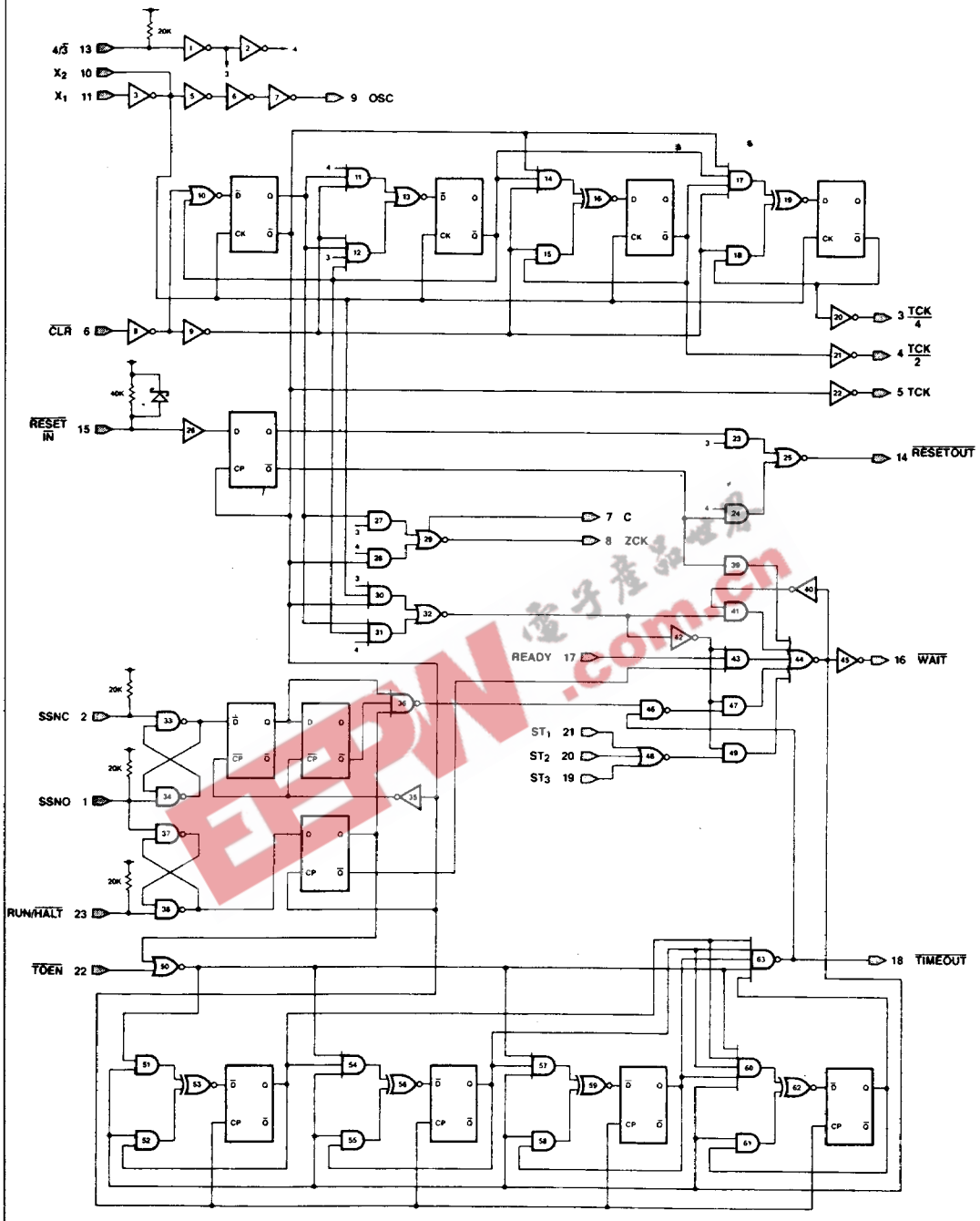
TYPICAL CRYSTAL SPEC

Mode	Fundamental AT cut
Resonance	Parallel or Series
Load	32pF (Net of 56pF C's shown + stray C)
Stability	±0.01% (or to user requirement)

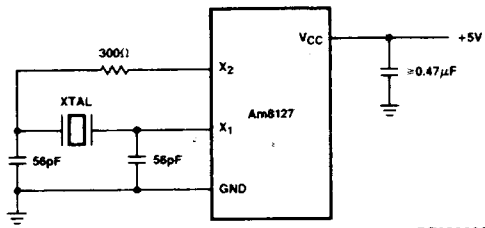
$\overline{WAIT}$, $\overline{TIMEOUT}$ FUNCTION TABLE

RUN/$\overline{HALT}$	SSNC	ST_3 ST_2 ST_1	READY	$\overline{TOEN}$	$\overline{TIMEOUT}$ COUNTER	$\overline{TIMEOUT}$	$\overline{WAIT}$
H	X	L L L	H	X	Cleared	H	H
		L L L	L	X	Cleared	H	H
		Any ST_i = H	H	L	Cleared	H	H
			L	H	Hold	H	L
			L	L	Count + 1 on ZCK ↓	H until 16 clocks after ready ↓, then LOW one ZCK period	L until 16 clocks after ready ↓, then HIGH one ZCK period
L	L	X	X	X	Hold	H	L
	H						HIGH one ZCK period

BLOCK DIAGRAM



CRYSTAL CONTROLLED OSCILLATOR



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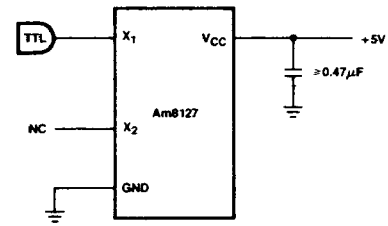
EXTERNAL CLOCK DRIVE



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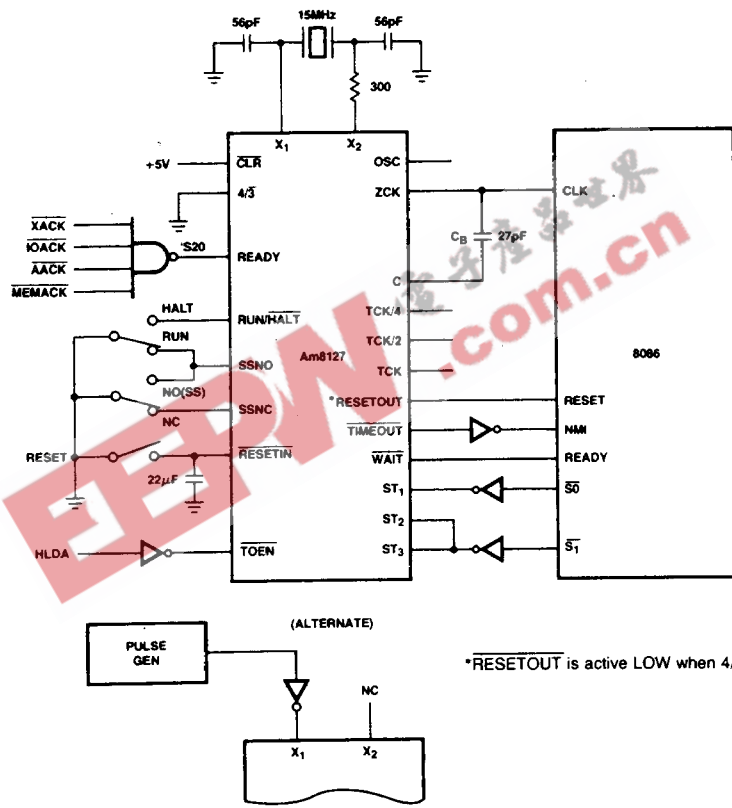
AmZ8000 APPLICATION

(50% Duty Cycle ZCK)



(ALTERNATE)

*$\overline{\text{RESETOUT}}$ is active LOW when $4/\overline{3}$ = HIGH

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The typical operating configuration for Am8127 is shown above. The component values shown provide a 4MHz clock output for the AmZ8002 CPU. The 27pF capacitor from C to ZCK is a bootstrap to ensure clock rise to V_{CC} −0.4V within the specified rise time. The 22μF reset capacitor is chosen to guarantee reset, plus adequate delay for reset during power-up with a slowly rising V_{CC} supply voltage. Ground SSNO if RUN/$\overline{\text{HALT}}$ or S-S isn't used.

ABSOLUTE MAXIMUM RATINGS

Storage Temperature ..... −65°C to +150°C
Temperature (Ambient) Under Bias ..... −55°C to +125°C
Supply Voltage to Ground Potential
(Pin 24 to Pin 12) Continuous ..... −0.5V to +7.0V
DC Voltage Applied to Outputs For
High Output State ..... −0.5V to +V_{CC} max
DC Input Voltage
X_1,4/$\overline{3}$, SSNO, SSNC, RUN/ $\overline{HALT}$ ..... −0.5V to V_{CC} +0.5V
Other Inputs ..... −0.5V to +5.5V
DC Voltage Applied to C ..... −0.5V to +8V
DC Output Current, Into Outputs 30mA
DC Input Current ..... −30mA to +5.0mA

Stresses above those listed under ABSOLUTE MAXIMUM RATINGS may cause permanent device failure. Functionality at or above these limits is not implied. Exposure to absolute maximum ratings for extended periods may affect device reliability.

OPERATING RANGES

Commercial (C) Devices
Temperature ..... 0°C to +70°C
Supply Voltage ..... +4.75V to +5.25V

Military (M) Devices
Temperature ..... −55°C to +125°C
Supply Voltage ..... +4.5V to +5.5V

Operating ranges define those limits over which the functionality of the device is guaranteed.

DC CHARACTERISTICS over operating range unless otherwise specified

Parameter	Description			Test Conditions (Note 1)		Min	Typ (Note 2)	Max	Units
V_{OH}	Output HIGH Voltage	V_{CC} = MIN	ZCK	I_{OH} = −0.1mA		V_{CC}−0.4	V_{CC}−0.1		Volts
			TTL Outputs	I_{OH} = −1mA	MIL	2.4	3.4		Volts
				I_{OH} = −2.6mA	COM'L				
V_{OL}	Output LOW Voltage	V_{CC} = MIN		I_{OL} = 0.1mA, ZCK Output				0.4	Volts
				I_{OL} = 16mA, TTL Output				0.5	Volts
V_{IH}	Input HIGH Level	Guaranteed input HIGH Voltage		$\overline{RESETIN}$		2.8	2.25		Volts
				ST_1, ST_2, ST_3, $\overline{CLR}$, $\overline{TOEN}$, X_1, READY		2.0			Volts
V_{IL}	Input LOW Level	Guaranteed input LOW Voltage		ST_1, ST_2, ST_3, CLR, $\overline{TOEN}$, X_1, READY				0.8	Volts
V_I	Input Clamp Voltage	V_{CC} = MIN, I_{IN} = −18mA (Note 3)						−1.5	Volts
V_{IN}−V_{IL}	$\overline{RESETIN}$ Hysteresis	V_{CC} = MIN				400	650		mV
I_{IL}	Input LOW Current	V_{CC} = MAX, V_{IN} = 0.4V		SSNO				−1.6	mA
				SSNC, 4/$\overline{3}$, RUN/$\overline{HALT}$, READY				−1.2	mA
				$\overline{TOEN}$, $\overline{CLR}$, X_1				−0.72	mA
				$\overline{RESETIN}$, ST_1, ST_2, ST_3				−0.36	mA
I_{IH}	Input HIGH Current	V_{CC} = MAX, V_{IN} = 2.7V		4/$\overline{3}$, SSNC, SSNO RUN/$\overline{HALT}$			(Note 4)	−300	μA
				$\overline{RESETIN}$			(Note 4)	−200	μA
				$\overline{CLR}$, READY, $\overline{TOEN}$ ST_1, ST_2, ST_3				+50	μA
				X_1				+600	μA
I_I	Input HIGH Current	V_{CC} = MAX, V_{IN} = 5.5V		$\overline{CLR}$, READY, $\overline{TOEN}$ ST_1, ST_2, ST_3				+1.0	mA
I_{SC}	Output Short Circuit Current (Note 5)	V_{CC} = MAX		ZCK Output		−50		−240	mA
				Others		−40		−130	mA
I_{CC}	Power Supply Current	V_{CC} = MAX		X_1 = 2.4V, ZCK = TCK's = LOW			95	140	mA
				Operating, f_{OSC} ≤ 24MHz (Note 6)			120	180	

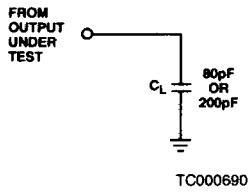
Notes: 1. For conditions shown as MIN or MAX, use the appropriate value specified under Operating Range for the applicable device type.
2. Typical limits are at V_{CC} = 5.0V, 25°C ambient and maximum loading.
3. Not applicable to X_1.
4. Specification is negative because of internal input pull-up resistors.
5. Not more than one output should be shorted at a time. Duration of the short circuit test should not exceed one second.
6. For oscillator frequencies up to 24MHz, outputs open.

STATIC INPUT ELECTRICAL CHARACTERISTICS

The static control inputs, SSNO, SSNC (Single Step), RUN/$\overline{\text{HALT}}$ and 4/$\overline{3}$ (clock duty cycle control), are Low-Power Schottky TTL compatible inputs with internal pull-up resistors to the +5V supply. They may be left open for a HIGH input (e.g., 4/$\overline{3}$ is left open for operation with AmZ8001/8002), or grounded for a LOW input. SSNO, SSNC and RUN/$\overline{\text{HALT}}$ are intended to be grounded or opened by switches. 4/$\overline{3}$ is normally left open for AmZ8001/8002. These inputs are specified at 0.4V/2.4V for test convenience.

Parameter	Description	Test Conditions		Min	Typ	Max	Units
V_{IH}	Input HIGH Voltage	Guaranteed HIGH input voltage	RUN $\overline{\text{HALT}}$, SSNO	2.4			Volts
V_{IL}	Input LOW Voltage	Guaranteed LOW input voltage	SSNC,4/$\overline{3}$			0.4	Volts

SWITCHING TEST CIRCUIT



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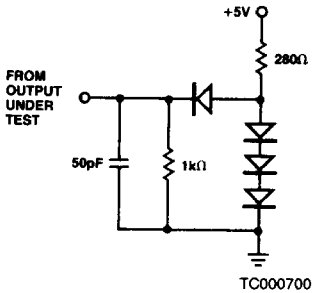
ZCK Output



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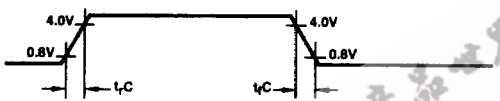
TTL Outputs

SWITCHING TEST WAVEFORMS

ZCK RISE AND FALL TIMES



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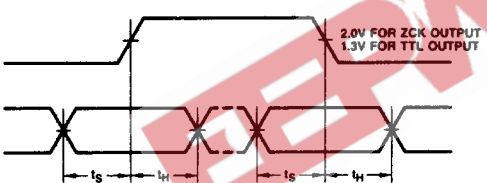
SET-UP AND HOLD TIMES



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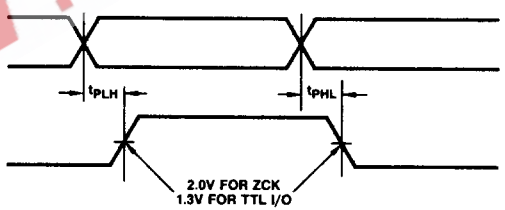
PROPAGATION DELAY TIMES



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SWITCHING CHARACTERISTICS —OSCILLATOR, $\overline{WAIT}$ AND ZCK OUTPUT

(T_A = +25°C, V_{CC} = 5.0V)

Parameters	Description		Test Conditions	Min	Typ	Max	Units
f_{MAX}	Oscillator Frequency		See Test Circuits (Note 7)	24			MHz
t_{rC}	ZCK Rise Time	C_L = 80pF	ZCK C_L = 80pF (Note 8)		9	14	ns
t_{fc}	ZCK Fall Time				7.6	11	ns
t_{rC}	ZCK Rise Time	C_L = 200pF	ZCK C_L = 200pF (Note 8)		15.4	20	ns
t_{fc}	ZCK Fall time				14.0	20	ns
t_{PLH}	READY to $\overline{WAIT}$		See Test Circuits		8	14	ns
t_{PHL}					11.5	16	ns
t_{PLH}	Status ST_i to $\overline{WAIT}$				13	17	ns
t_{PHL}					17.2	21	ns
t_S	$\overline{CLR}$ to OSC (⎍) Setup Time				15	18	ns
t_H	$\overline{CLR}$ to OSC (⎍) Hold Time				−11	−6	ns

Notes: 7. Specification is based on fundamental mode crystal. See application section.
8. ZCK rise and fall times are based on a bootstrap capacitor value of 27pF.

SWITCHING CHARACTERISTICS — 4/$\overline{3}$ = HIGH (AmZ8000 Mode)

(T_A = +25°C, V_{CC} = 5.0V)

Parameters	Description		Test Conditions	Min	Typ	Max	Units
t_S	READY to ZCK Set-up Time	(Note 9)	See Test Circuits ZCK C_L = 80pF	T/4 + 10	T/4 + 4.5		ns
t_H	READY to ZCK Hold Time			T/4 + 2	T/4		ns
t_S	Status ST_i to ZCK Set-up Time			T/4 + 12	T/4 + 9.5		ns
t_H	Status ST_i to ZCK Hold Time			T/4 – 3	T/4 – 7.5		ns
t_S	$\overline{TOEN}$ to ZCK Set-up Time			30	22		ns
t_H	$\overline{TOEN}$ to ZCK Hold Time			–10	–16		ns
t_{SKEW}	ZCK to OSC			3	6	10	ns
t_{SKEW}	ZCK to TCK			0	4.0	7	ns
t_{PLH}	ZCK to $\overline{RESET\ OUT}$ Propagation Delay				9.0	13	ns
t_{PHL}					4	8	ns

Note: 9. T = ZCK period.

SWITCHING CHARACTERISTICS OVER OPERATING RANGE — OSCILLATOR, $\overline{WAIT}$ AND ZCK OUTPUTS*

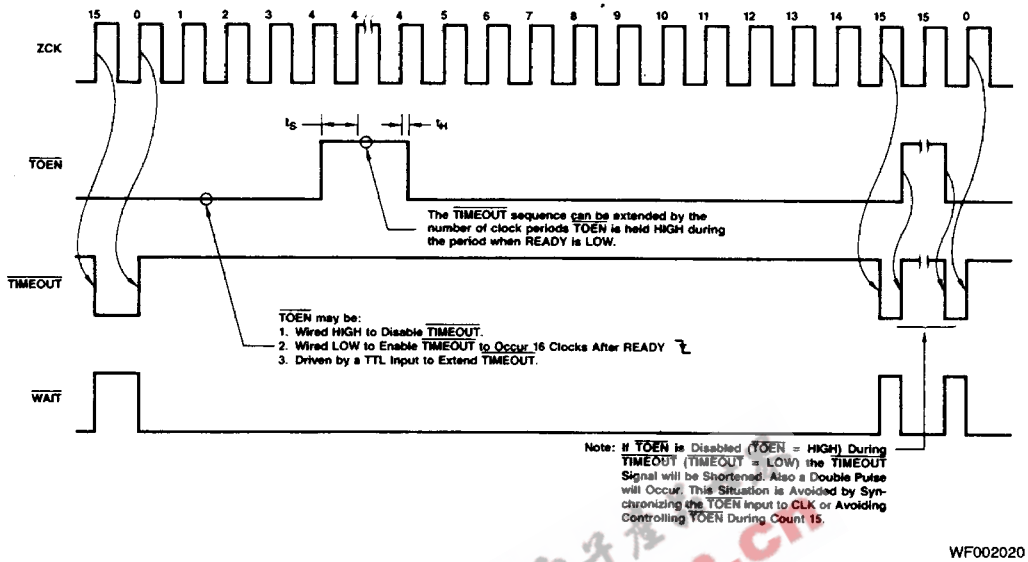
Parameters	Description		Test Conditions	COMMERCIAL Min	COMMERCIAL Max 0°C	COMMERCIAL Max 70°C	MILITARY Min	MILITARY Max –55°C	MILITARY Max 125°C	Units
t_{MAX}	Oscillator Frequency		(Note 7)	24			24			MHz
t_{rC}	ZCK Rise Time	C_L = 80pF	C_L = 80pF (Note 8)		15	15		20	15	ns
t_{fC}	ZCK Fall Time				14	14		20	14	ns
t_{rC}	ZCK Rise Time	C_L = 200pF	C_L = 200pF (Note 8)		25	20		32	20	ns
t_{fC}	ZCK Fall time				25	20		32	20	ns
t_{PLH}	READY to WAIT Propagation Delay		See Test Circuits		17	17		19	19	ns
t_{PHL}					19	19		19	19	ns
t_{PLH}	Status ST_i to $\overline{WAIT}$ Propagation Delay				20	20		22	22	ns
t_{PHL}					25	25		25	25	ns
t_S	$\overline{CLR}$ to OSC (⎍) Setup Time			21			30			ns
t_H	$\overline{CLR}$ to OSC (⎍) Hold Time			–3			0			ns

*AC performance over the operating temperature range is guaranteed by testing defined in Group A, Subgroup 9.

SWITCHING CHARACTERISTICS OVER OPERATING RANGE — 4/$\overline{3}$ = HIGH (AmZ8000 Mode)

Parameters	Description	Test Conditions	COMMERCIAL Min	COMMERCIAL Max	MILITARY Min	MILITARY Max	Units
t_S	READY to ZCK Setup Time	See Test Circuits ZCK, C_L = 80pF	T/4 + 14		T/4 + 17		ns
t_H	READY to ZCK Hold Time		T/4 + 5		T/4 + 5		ns
t_S	Status ST_i to ZCK Setup Time		T/4 + 15		T/4 + 20		ns
t_H	Status ST_i to ZCK Hold Time		T/4		T/4 + 5		ns
t_S	$\overline{TOEN}$ to ZCK Setup Time		35		40		ns
t_H	$\overline{TOEN}$ to ZCK Hold Time		–5		0		ns
t_{SKEW}	ZCK to OSC Skew		2	14	2	17	ns
t_{SKEW}	ZCK to TCK Skew		–2	10	–2	14	ns
t_{PLH}	ZCK to $\overline{RESETOUT}$ Propagation Delay			16		20	ns
t_{PHL}				16		20	ns

$\overline{\text{TIMEOUT}}$ COUNTER TIMING



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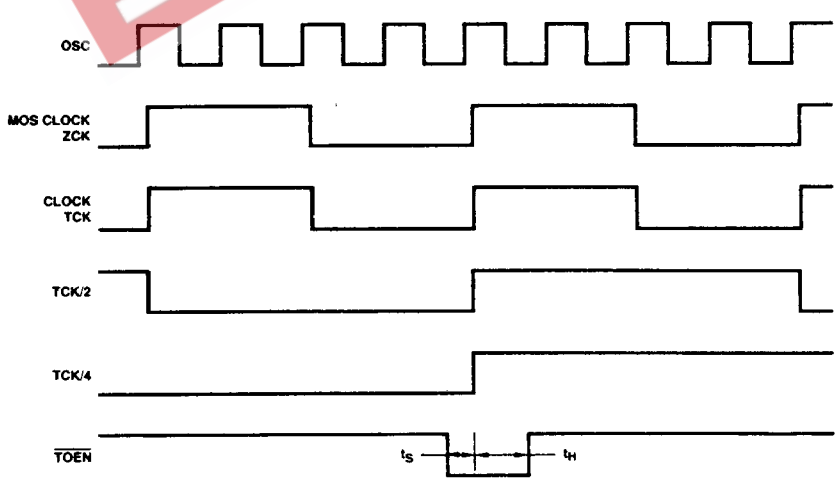
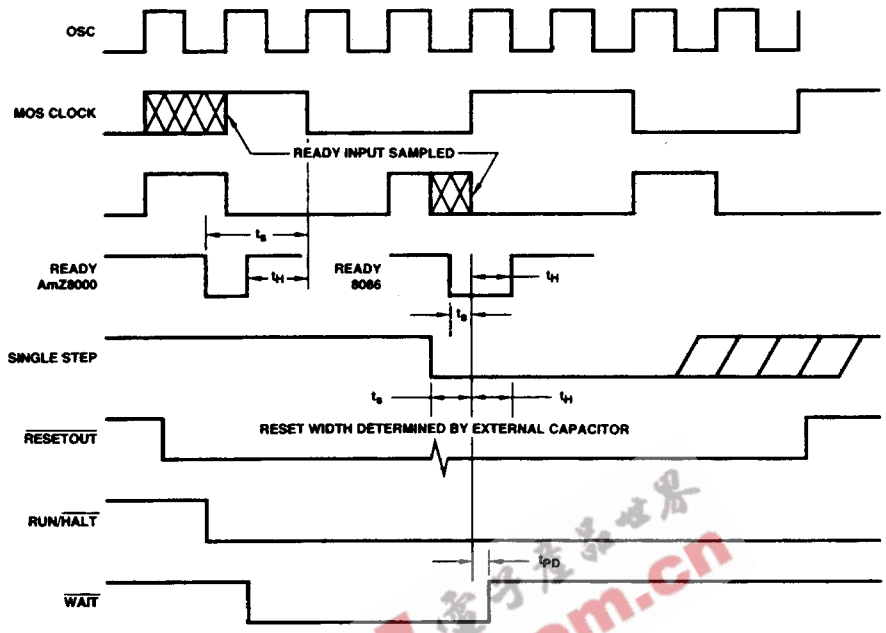
Am8127 CLOCK OUTPUTS
DIVIDE BY 4 MODE (AmZ8000)



WF002030

Am8127 READY, WAIT, RESET, AND SINGLE STEP



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